# Statistical Data Analysis 2020/21 Lecture Week 4



London Postgraduate Lectures on Particle Physics University of London MSc/MSci course PH4515



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Course web page via RHUL moodle (PH4515) and also www.pp.rhul.ac.uk/~cowan/stat\_course.html Statistical Data Analysis Lecture 4-1

- Frequentist statistical tests
  - Hypotheses
  - Definition of a test
    - critical region
    - size
    - power
  - Type-I, Type-II errors

## Hypotheses

A hypothesis *H* specifies the probability for the data, i.e., the outcome of the observation, here symbolically: *x*.

x could be uni-/multivariate, continuous or discrete.

E.g. write  $x \sim P(x|H)$ .

x could represent e.g. observation of a single object, a single event, or an entire "experiment".

Possible values of x form the sample space S (or "data space").

Simple (or "point") hypothesis: P(x|H) completely specified.

**Composite hypothesis**: *H* contains unspecified parameter(s).

P(x|H) is also called the likelihood of the hypothesis H, often written L(H) if we want to emphasize just the dependence on H.

## Definition of a test

Goal is to make some statement based on the observed data x about the validity of the possible hypotheses (here, "accept or reject").

Consider a simple hypothesis  $H_0$  (the "null") and an alternative  $H_1$ .

A test of  $H_0$  is defined by specifying a critical region W of the sample (data) space S such that there is no more than some (small) probability  $\alpha$ , assuming  $H_0$  is correct, to observe the data there, i.e.,

 $P(x \in W \mid H_0) \le \alpha$ 

 $\alpha$  is called the size of the test, prespecified equal to some small value, e.g., 0.05.

If x is observed in the critical region, reject  $H_0$ .



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## Definition of a test (2)

But in general there are an infinite number of possible critical regions that give the same size  $\alpha$ .

Use the alternative hypothesis  $H_1$  to motivate where to place the critical region.

Roughly speaking, place the critical region where there is a low probability ( $\alpha$ ) to be found if  $H_0$  is true, but high if  $H_1$  is true:



## Obvious where to put *W*?

In the 1930s there were great debates as to the role of the alternative hypothesis.

Fisher held that one could test a hypothesis  $H_0$  without reference to an alternative.

Suppose, e.g.,  $H_0$  predicts that x (suppose positive) usually comes out low. High values of x are less characteristic of  $H_0$ , so if a high value is observed, we should reject  $H_0$ , i.e., we put W at high x:



## Or not so obvious where to put W?

But what if the only relevant alternative to  $H_0$  is  $H_1$  as below:



Here high x is more characteristic of  $H_0$  and not like what we expect from  $H_1$ . So better to put W at low x.

Neyman and Pearson argued that "less characteristic of  $H_0$ " is well defined only when taken to mean "more characteristic of some relevant alternative  $H_1$ ".

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## Type-I, Type-II errors

Rejecting the hypothesis  $H_0$  when it is true is a Type-I error.

The maximum probability for this is the size of the test:

 $P(x \in W \mid H_0) \leq \alpha$ 

But we might also accept  $H_0$  when it is false, and an alternative  $H_1$  is true.

This is called a Type-II error, and occurs with probability

 $P(x \in \mathbf{S} - W \mid H_1) = \beta$ 

One minus this is called the power of the test with respect to the alternative  $H_1$ :

Power =  $1 - \beta$ 

## Rejecting a hypothesis

Note that rejecting  $H_0$  is not necessarily equivalent to the statement that we believe it is false and  $H_1$  true. In frequentist statistics only associate probability with outcomes of repeatable observations (the data).

In Bayesian statistics, probability of the hypothesis (degree of belief) would be found using Bayes' theorem:

$$P(H|x) = \frac{P(x|H)\pi(H)}{\int P(x|H)\pi(H) \, dH}$$

which depends on the prior probability  $\pi(H)$ .

What makes a frequentist test useful is that we can compute the probability to accept/reject a hypothesis assuming that it is true, or assuming some alternative is true.

# Statistical Data Analysis Lecture 4-2

- Particle Physics example for statistical tests
- Statistical tests to select objects/events

## Example setting for statistical tests: the Large Hadron Collider



Detectors at 4 pp collision points: ATLAS CMS general purpose LHCb (b physics) ALICE (heavy ion physics) Counter-rotating proton beams in 27 km circumference ring

### pp centre-of-mass energy 14 TeV



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# The ATLAS detector

# 3000 physicists38 countries183 universities/labs



Toroid Magnets Solenoid Magnet SCT Tracker Pixel Detector TRT Tracker



 $\begin{array}{l} 25 \ m \ \text{diameter} \\ 46 \ m \ \text{length} \\ 7000 \ \text{tonnes} \\ \sim 10^8 \ \text{electronic channels} \end{array}$ 

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## A simulated SUSY event



## **Background events**



This event from Standard Model ttbar production also has high  $p_{\rm T}$  jets and muons, and some missing transverse energy.

→ can easily mimic a signal event.

### Classification viewed as a statistical test

Suppose events come in two possible types:

s (signal) and b (background)

For each event, test hypothesis that it is background, i.e.,  $H_0 = b$ .

Carry out test on many events, each is either of type s or b, i.e., here the hypothesis is the "true class label", which varies randomly from event to event, so we can assign to it a frequentist probability.

Select events for which where  $H_0$  is rejected as "candidate events of type s". Equivalent Particle Physics terminology:

background efficiency  $arepsilon_{
m b} = \int_W f({f x}|H_0)\,d{f x} = lpha$ 

$$\varepsilon_{\mathbf{s}} = \int_{W} f(\mathbf{x}|H_1) \, d\mathbf{x} = 1 - \beta = \text{power}$$

signal efficiency

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## Example of a test for classification



For each event in a mixture of signal (s) and background (b) test

 $H_0$ : event is of type b

using a critical region W of the form:  $W = \{x : x \le x_c\}$ , where  $x_c$  is a constant that we choose to give a test with the desired size  $\alpha$ .

## Classification example (2)

Suppose we want  $\alpha = 10^{-4}$ . Require:

$$\alpha = P(x \le x_{c}|b) = \int_{0}^{x_{c}} f(x|b) \, dx = \frac{4x^{4}}{4} \Big|_{0}^{x_{c}} = x_{c}^{4}$$

and therefore  $x_{\rm c} = \alpha^{1/4} = 0.1$ 

For this test (i.e. this critical region W), the power with respect to the signal hypothesis (s) is

$$M = P(x \le x_{\rm c}|{\rm s}) = \int_0^{x_{\rm c}} f(x|{\rm s}) \, dx = 2x_{\rm c} - x_{\rm c}^2 = 0.19$$

Note: the optimal size and power is a separate question that will depend on goals of the subsequent analysis.

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## Classification example (3)

Suppose that the prior probabilities for an event to be of type s or b are:

 $\pi_{\rm s} = 0.001$  $\pi_{\rm b} = 0.999$ 

The "purity" of the selected signal sample (events where b hypothesis rejected) is found using Bayes' theorem:

$$P(\mathbf{s}|x \le x_{\mathbf{c}}) = \frac{P(x \le x_{\mathbf{c}}|\mathbf{s})\pi_{\mathbf{s}}}{P(x \le x_{\mathbf{c}}|\mathbf{s})\pi_{\mathbf{s}} + P(x \le x_{\mathbf{c}}|\mathbf{b})\pi_{\mathbf{b}}}$$

= 0.655

## Classification example (4)

Suppose an individual event is observed at x = 0.1. What is the probability that this event is background?

$$P(\mathbf{b}|x) = \frac{f(x|\mathbf{b})\pi_{\mathbf{b}}}{f(x|\mathbf{b})\pi_{\mathbf{b}} + f(x|\mathbf{s})\pi_{\mathbf{s}}}$$

$$=\frac{4x^3\pi_{\rm b}}{4x^3\pi_{\rm b}+2(1-x)\pi_{\rm s}}$$

= 0.689

(Here nothing to do with the test using  $x \le x_c$ , just an illustration of Bayes' theorem.)